

Notice of References Cited

Application/Control No.

10/565,601

Applicant(s)/Patent Under
Reexamination
TANAKA ET AL.

Examiner

JOSEPH NGUYEN

Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,507,057	01-2003	Ohno, Seiji	257/257
*	B	US-6,414,431	07-2002	Yu et al.	313/504
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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